

Note: This Sole Source Certification will become a public document, open to public inspection; therefore, you should be certain all material facts are true, relevant and clearly understandable.

SOLE SOURCE CERTIFICATION

Under the requirement of University of Florida Rule No. 6C1-3.020(5)(f)(2), the following is submitted in support of this request for authority to purchase, without bidding, the items available from only one source.

Note: Sole Source means that the item/service is unique and that the vendor is the only one from whom the item/service can be provided. Best Price alone cannot be used for sole source. If the item/service is available from more than one source of supply, best price must be determined through the competitive bid process.

A. Sole Source Vendor Company Name: MicroXact, Inc.
Contact Person: Vladimir Kochergin
Address: 6580 Valley Center Drive Suite 312 Radford, VA 24141
Telephone: (614) 917-7202 Fax: (614) 917-7202 Email: vkochergin@microxact.com

B. Describe in lay language, what the item/service is and how it is to be used in your area of research. (cont. P2)
This system is a high temperature probe station for performing current-voltage and capacitance-voltage testing of semiconductor wafers and chips under DC or AC conditions. The measurement area is 2", the temperature is controllable up to 1000C, and the atmosphere in the chamber can be controlled via vacuum pumps and inert gas injection.

C. What feature or special condition of this commodity/service is unique and cannot be obtained from any other source? (cont. P2)
We require ability to measure electrical behavior of semiconductor devices over a 2" diameter area. No other source has the ability to measure a sample of this size. We require the ability to control the environment in the chamber. No other source has the ability to inject inert gases. We require the ability to test under DC and AC bias conditions. Other sources investigated can only perform measurements in DC mode. My research involves studying thermal stability of semiconductor materials at the 2" wafer scale, quantified by electrical testing of DC and AC behavior under varying environments, thus necessitating the unique features of this system.

D. Is this product being purchased directly from the manufacturer? [X] Yes [] No
If No, is it available from more than one dealer? [] Yes [] No
If Yes, it is available from more than one dealer, why can this item not be bid? (cont. P2)

E. Prior to submitting this requisition, did you investigate other possible sources? [X] Yes [] No
If Yes: 1) Did you obtain quotes from the other sources? [] Yes [X] No If Yes, attach copies.
2) Is this Vendor's price lower than the other sources? [] Yes [] No If No, justify the additional cost below.
Other potential sources were investigated; however, none were able to simultaneously accommodate both the size (2" diameter wafer) and temperature requirements (~1000°C) needed for the research being performed. No other sources were able to meet the requirements of measurement area or ability to control the atmosphere in the chamber, or perform measurements in both AC and DC mode.

F. Other Sole Source comments or explanations. (cont. P2)
Opted for a 4-probe configuration as opposed to a 6-probe setup. The additional 2 probes were microwave probes, which added substantial cost. Removal of this option is estimated to have removed approximately 5% of the total cost of the system.

I / We, the undersigned, certify the above to be true and correct to the best of my / our knowledge and belief and the user and / or undersigned does not have a financial interest in the above named vendor.

Table with 2 columns: DEPARTMENT APPROVAL and PURCHASING APPROVAL. Includes signatures and dates for Principal Investigator, Purchasing Coordinator, and Purchasing Authorized Signature.

Sole Source Certification (Continued)

Please use the following sections to continue documentation if needed.

B. continued

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C. continued

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D. continued

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E. continued

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F. continued

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